

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 2002-117697

(43)Date of publication of application : 19.04.2002

(51)Int.Cl.

G11C 29/00
G01R 31/28
G06F 12/16
H01L 27/04
H01L 21/822

(21)Application number : 2000-307339

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(22)Date of filing : 06.10.2000

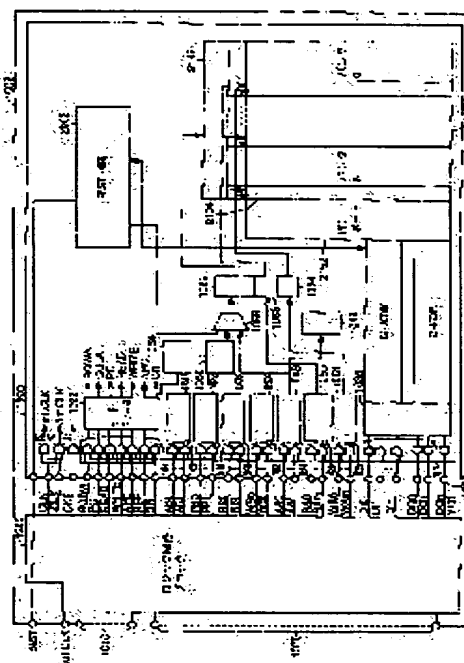
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(54) SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To provide a semiconductor integrated circuit device, provided with a built-in test circuit, with which a defective memory cell can be replaced by a redundant memory cell.

SOLUTION: After data has been written in a memory cell array according to an internal address signal, in read-out operation, read-out data from each memory cell is compared with expected value data. A row decoder 2142 selects plural memory cells, belonging to the same row of the memory cell array en bloc according to the address signal. A BIST circuit 2002 discriminates carrying out of relieving in a spare memory cell row, rather than in a spare memory cell column, when plural defective memory cells are detected in plural memory cells selected en bloc.



LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's
decision of rejection]

[Date of extinction of right]

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